

IFW/2855

PATENT



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS: THOMAS CHUDоба ET AL

SERIAL No.: 10/532,630 Group 2855

FILED : September 7, 2005

TITLE : TEST TABLE FOR MEASURING LATERAL FORCES AND
DISPLACEMENTS

SECOND SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

MAIL STOP Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

Further to the Information Disclosure Statement (IDS) filed on April 25, 2005, and the Supplemental IDS filed on April 19, 2006, applicants submit herewith a copy of Form PTO-1449 previously filed with the April 19, 2006 IDS along with a copy of the article "Microscratch and Load Relaxation Tests for Ultra-Thin Films." Since the instant Second Supplemental IDS is being filed before the issuance of a first Office Action, no fee is due. However, if it is determined that a fee is due, the Commission for Patents is hereby authorized to charge our deposit account No. 03-2468 or to credit any overpayment.

Respectfully submitted,
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I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: MAIL STOP Amendment, COMMISSIONER FOR PATENTS, P.O. Box 1450, Alexandria, VA 22313-1450, on May 12, 2006.

Kelly Espitia

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.:

SERIAL NO.:

CHUDоба, et al PCT

10/532,630

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT: Thomas Chudoba et al

FILING DATE: Sept. 7, 2005 GROUP: 2855

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,051,594	09/1991	Fumihiko et al			
	AB	4,157,818	06/1979	Key			
	AC	3,201,980	08/1965	Webb			
	AD	5,343,748	09/1994	Keasey, et al.			
	AE	2,573,286	10/1951	Baker, et al.			
	AF						
	AG						
	AH						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL	WO 02 16907	02/2002	PCT	ENCLOSED			
	AM	WO 99 46576	09/1999	PCT	ENCLOSED			
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	"Microscratch and Load Relaxation Tests for Ultra-Thin Films" - Wu T. W. Journal of Materials Research, New York, NY, U.S., Vol. 6, no. 2, pages 407-426 February 1991 (To follow) ENCLOSED 5-12-06
	AR	International Search Report
	AS	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.